

**Joint ICTP-IAEA Advanced Workshop on High Sensitivity 2D & 3D  
Characterisation and Imaging with Ion Beams | (smr 2856)**

Contribution ID : 10

Type : **not specified**

**Poster presentations: short oral presentation by  
each participant**

*Tuesday, 27 September 2016 14:00 (2:00)*

**Content**

**Summary**

**Presenter(s) :** ALL PARTICIPANTS AND FACULTY

**Session Classification :** DAY 2